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Technical Report

TECHNICAL REPORT INSTRUMENTATION VALIDATION

May 1979

BROWN ENGINEERING

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TECHNICAL REPORT ED79-ADTC-2334

TECHNICAL REPORT INSTRUMENTATION VALIDATION

May 1979

Prepared For

ARMAMENT DEVELOPMENT AND TEST CENTER EGLIN AIR FORCE BASE, FLORIDA

Contract No. F08635-77-C-0293, P00010 Data Item B004

Prepared By

ELECTRONICS DIVISION
TELEDYNE BROWN ENGINEERING
HUNTSVILLE, ALABAMA

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1. INTRODUCTION

This report is written to fulfill the requirements of Data Item B004 of Contract No. F08635-77-C-0293. The report covers the work performed under Task 7 - Validate Instrumentation of Contract Modification P00010. This work was performed during March and April 1979 at the GVT Facility at Eglin Air Force Base.

An analytic and test validation was performed on the GVT Facility instrumentation. The purpose of the test was to determine the capability of the GVT System to perform its intended mission of dynamic analysis of aircraft structures. Each element of the system was examined to determine its individual function as well as its intended and unintended interaction with every other element of the system. The system was tested for signal input accuracy, cable integrity, grounding, noise susceptibility, and output signal integrity. All components were found to be well-maintained and functioning properly. The only discrepancies found in the system relate to system analog grounding. Recommended corrective measures to eliminate these discrepancies are outlined.

With the implementation of the recommendations contained in this report, the GVT should be an excellent tool for dynamic analysis of aircraft structures and the instrumentation should provide constant, repeatable results under all test conditions.

2. WORK APPROACH

The facility validation task was broken down into the following sequence of individual tasks: Problem Definition, System Definition, Test Development, Testing, Test Results Analysis, Retest and Validation, and Recommendations for Corrective Action.

A meeting was held with GVT personnel to obtain a better understanding of the function of the system and the way it was utilized.

Areas discussed included normal system configuration, test setup, problem areas encountered in testing, system performance, and test results validity. From these discussions it was determined that an independent evaluation of the ability of the system to provide accurate, repeatable, and reliable results was needed.

2.1 PROBLEM DEFINITION

Based on the requirement for an independent evaluation of the GVT instrumentation system performance, further discussions were held to determine the problems that had been experienced in the past and to try to classify these problems as to their cause and impact on system performance. The following areas were identified as potential areas for further evaluation and test:

- Noise on some transducers under some test conditions
- Lack of calibration data on
 - ▲ Input preamplifiers
 - ▲ Output power amplifiers
- Uncertainty over the effects of cable grounding
- Uncertainty over the effects of system ac power wiring
- Low-level shaker excitation with no input command when shaker amplifiers were powered from test floor.

2.2 SYSTEM DEFINITION

To properly understand the functional relationship existing between components of the GVT instrumentation, functional diagrams of the input and output signal flow were developed. These were reviewed with the GVT personnel to clarify the exact methodology used in interconnecting various elements and to obtain their insight into how various operating configurations contributed to system performance. These functional diagrams are presented in Figure 2-1 (signal input block diagram) and Figure 2-2 (excitation outputs block diagram). These diagrams were then used in defining all testing approaches and recommendations.

2.3 TEST DEVELOPMENT

A test approach was developed that would utilize the system as configured to examine the problem areas identified as well as provide an insight into any other system performance restrictions that might exist. The integrity of all input and output signals should be verified as well as the cabling. To accomplish this, four basic tests were developed, as shown in Table 2-1.

TABLE 2-1. FOUR BASIC TESTS FOR GVT

QUANTITY	COMPONENT	TEST TO BE PERFORMED
200	Cables	Short-circuit resistance, insulation resistance
32	Input Preamplifiers	Gain, frequency response, distortion
4	Power Amplifiers	Gain, frequency response, distortion
	System	Grounding and inter-rack ambient noise level

Based on the results of these tests, a full-scale examination of the system would be conducted to determine how each component contributed to the total system performance. The results of these tests are covered under test results (Section 3) and the test data are contained in the attached appendices.

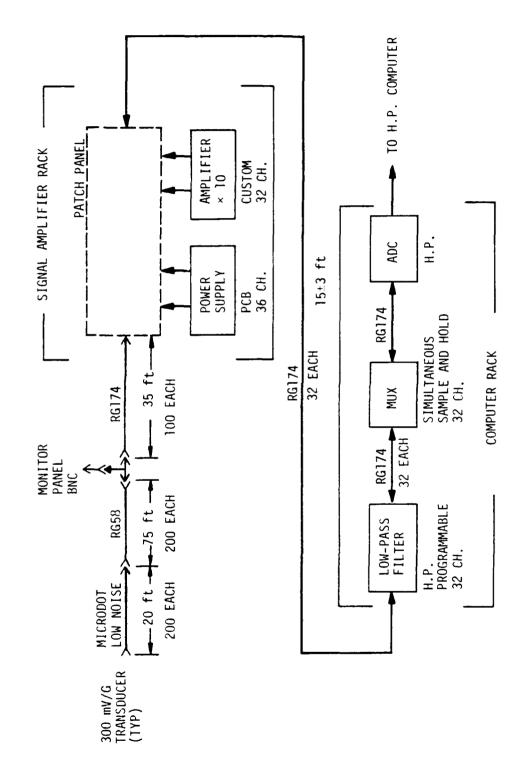
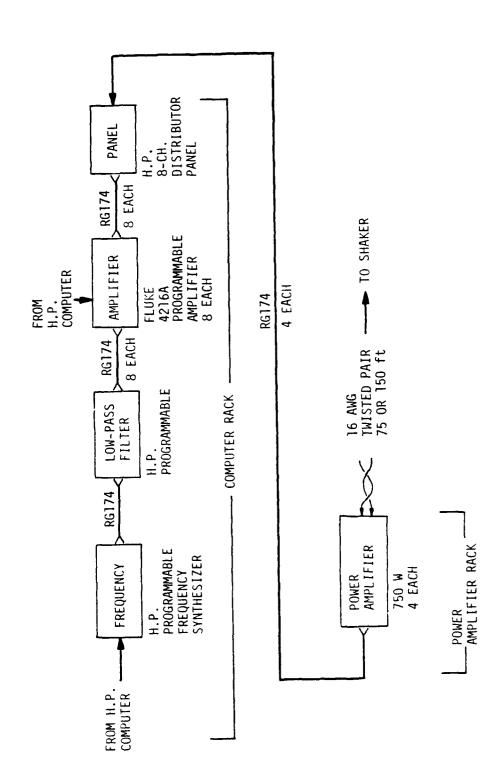


FIGURE 2-1. SIGNAL INPUT BLOCK DIAGRAM



.

3

FIGURE 2-2. EXCITATION OUTPUT BLOCK DIAGTAM

3. TESTING AND TEST RESULTS

The following paragraphs discuss the detailed testing performed on the GVT instrumentation as well as the general conclusions reached about the performance of the individual components being tested.

3.1 CABLE TEST

An easily implementable and repeatable test was required to verify the integrity of all coaxial cables from the test floor to the system patch panel. After examination of the characteristics of the cable used (RG58, RG174, and Microdot Lo Noise) and the test frequencies of interest (0 to 200 Hz), it was determined that the characteristics that could be most detrimental to test results were dc resistance of the coaxial cable and insulation resistance.

The dc resistance test was conducted with one end of the cable shorted. This allowed the measurement of shield and center conductor resistance as well as all terminations (crimp and solder) in the cable run. As shown in the test results, the resistance is very repeatable from cable to cable. Table 3-1 lists the range of acceptable values for various configurations as well as those cables that are suspect and that should be examined for poor terminations.

TABLE 3-1. RANGE OF ACCEPTABLE VALUES

FROM	ТО	ACCEPTABLE VALUE (ohms)	SUSPECT CABLE NO.
Floor	Patch Panel	4.3 to 5.9	3, 30, 40, 52, 86
Transducer	Patch Panel	9.0 to 10.0	40, 52
Floor	Breakout Panel	1.2 to 1.6	152

The Meggar test was conducted with the cable unterminated. This test measures the conductor-to-shield insulation resistance at 500 Vdc and will indicate shortened cables, crushed insulation, and contaminated connectors and terminations. Any value over 1 kMohm is acceptable.

Cable No. 40 was found to be bad. Cables 184 to 196 exhibited a higher (1.6-ohm) resistance than cables 101 to 185, probably because a different brand of connector was used. This should present no problems with signal transmission.

Appendix A contains the test procedure and all test data taken.

3.2 INPUT PREAMPLIFIER TEST

The input preamplifiers were tested to determine their ability to accurately amplify and reproduce the transducer signal. Each amplifier was tested at 30, 300, and 600 mV input signal at the following frequencies: 2, 10, 20, 30, 40, 80, 140, and 200 Hz. The output amplitude was measured and the amplifiers were found to have a gain of 10.6 to 1 uniformly. This gain rolled off to 10.3 to 1 at 2 Hz at all amplitudes and increased to 11 to 1 at 600 mV input. These changes are insignificant to the testing being conducted.

The distortion of each amplifier was measured at 300 mV input at 20, 80, and 200 Hz and was found to be less than 0.4% for all amplifiers. This level of distortion is insignificant to the testing being conducted by the facility.

Appendix B contains the test procedure and all test data taken.

3.3 GROUNDING TEST

After preliminary investigations of system performance and discussion of previous system problems with GVT Facility personnel, it was determined that the potential existed for ground noise between components of the GVT Facility. The tests of Appendix C were conducted. These tests indicated that the primary potential difference existed between the test

stand and the instrumentation. These tests also indicated that insufficient grounding existed between GVT components. As shown by the test data, addition of a ground strap reduced this noise by 66%.

Subsequent testing of ground potential differences and ground noise using the power spectral density measurement capability of the GVT computer revealed that 60-Hz ac power ground potential differences were the cause of the noise measured in the above test. Inadvertent shorting of the transducer-case-to-test-stand ground would then be the primary cause of error in GVT testing. The correction of this problem is addressed in Section 4.

3.4 POWER AMPLIFIER TEST

The power amplifiers were tested to determine their ability to accurately and repeatably provide the drive signal to the shakers at the required power levels. Each amplifier was tested at output power levels of 10, 50, and 100 W at excitation frequencies of 2, 10, 20, 30, 40, 80, 140, and 200 Hz. They were all found to have a flat response to 10 Hz, with some power amplification at 2 Hz. This amplification is not caused by the amplifier but by the dc resistance of the shaker coil at this low frequency.

The amplifier distortion measured at 50 W output power at 20. 100, and 200 Hz was found to be less than 0.6%. This distortion level is insignificant to the testing being conducted. The phase shift was measured at 20, 100, and 200 Hz at 100 W output power and was found to be zero at the higher frequencies and only 7 deg at 20 Hz. This phase shift should not affect test results or excitation characteristics.

3.5 TEST RESULTS ANALYSIS

The test data contained in the appendices were examined to determine if each component was making a proper contribution to GVT instrumentation performance. The only area identified that required further

investigation was system grounding. The potential difference between system components, especially between the test stand and the preamplifier rack, was much too high for good, consistent low-level signal measurement.

All other component testing verified that the equipment was functioning properly and was fully capable of performing the GVT mission.

3.6 RETEST AND VALIDATION

A retest of the input system with transducers connected was conducted to examine the effect of ground noise found in initial testing on system performance. This test was conducted in two phases: 1) ground potential measurement and 2) transducer signal impact.

The ground potential between the aircraft grounding lugs in the test floor and the legs of the test stand was measured. The potential between lugs ranged from 1 to 5 mV rms and between lugs and the test stand ranged from 7 to 12 mV rms. This measurement indicates that the test stand has no common ground and that the test stand is not connected to the grounding lugs in the floor. The structural modifications to be made to the test stand along with the recommendations made later in this report should reduce this noise to acceptable levels (1 to 3 mV rms).

The system was then configured for a power spectral density (PSD) test. An accelerometer and load cell were connected to two input amplifier channels. The transducers were held on the test floor on an isolation pad and the signal output was monitored at the transducer power supply with an oscilloscope. The noise level from both transducers was less than 1 mV peak-to-peak. The computer-run PSD test indicated that what coherent noise existed was centered at 60 Hz.

The transducer cases were individually shorted to the test stand. The noise increased to 50 mV peak-to-peak, with the primary frequency at 60 Hz and a secondary contribution at 180 Hz (third harmonic). When both cases were shorted together and then shorted to the test stand, the noise was reduced to 40 mV peak-to-peak.

With the transducer cases shorted together and to the test stand, an 8 AWG (3 No. 12 AWG) ground strap was connected between the test stand and the preamplifier rack. The noise level was reduced to 10~mV peak-topeak with the same 60- and 180-Hz frequency content.

Based on these measurements, it was concluded that the only problem with the system was one of 60-Hz power grounding and that the system, through its PSD measurement capability, could be configured to monitor its own ground noise condition. No problems should be encountered with the present configuration as long as care is taken to ensure that all transducers are isolated from the test stand ground.

4. CONCLUSIONS AND RECOMMENDATIONS

4.1 CONCLUSIONS

The GVT instrumentation as configured will perform accurate, repeatable tests and will provide reliable, consistent results provided all transducers are electrically isolated from the test item. As currently configured, up to 50 mV peak-to-peak of 60-Hz noise will be injected on transducer liners that are shorted to the test item or the structure.

During testing, it was demonstrated that these noise levels could be substantially reduced by revision of the system grounding. The revision to system grounding and isolation are the major recommendations derived from these test and analysis efforts. Implementation of these recommendations should remove all test anomalies.

Measures should be taken to reduce this 60-Hz noise by reducing the ground potential difference between system elements.

4.2 RECOMMENDATIONS

Only two recommendations for revisions to equipment or procedures have been identified as potential improvements to system performance. The basic system, including all cables, transducers, and electronics, was found to be sound and properly maintained. The recommendations deal with reduction of system 60-Hz ground differential voltage and with the isolation of all test transducers.

4.2.1 Transducer Isolation

It was found that accelerometers are generally installed on isolation studs; however, no attempt is made at present to verify that ground isolation is achieved. A procedure should be instituted whereby each transducer's isolation is verified with an ohmmeter prior to connection of that transducer's cable.

The load cell placed between the shaker and the test specimens is not currently isolated since it is bolted directly to the load transfer pads. A nonconductive shim should be placed between this pad and the test specimens to ensure electrical isolation. This isolation should be verified prior to connection of the load cell cable in the same manner as the transducer. If a nonisolated shaker is used, then similar precautions should be taken between the shaker and the load cell.

4.2.2 60-Hz Noise and Grounding

The 60-Hz noise can be traced to two sources: 1) the lack of a common analog ground system and 2) the lack of a common instrumentation power source. Because the GVT facility was installed in an existing facility, not all ac power is derived from a single power panel with common ground. This presents a condition wherein chassis ground differences can develop and vary according to electrical loads in other parts of the building not controlled by GVT Facility personnel. To alleviate this problem, the ac wiring servicing the GVT Facility should be revised to provide a common power distribution point for all instrumentation with no other, nonfacility equipments attached.

No consideration has been given to establishing a common analog ground for the system separate from the ac third-wire safety ground. Tests have shown (Appendix C) that ground noise can be substantially reduced by installation of an analog grounding system. The recommended grounding scheme is shown in Figure 4-1 and implemented as follows:

- A ground bus should be installed in the signal power supply and amplifier rack.
- A 6 AWG wire should be run from a welded lug on the test stand to the ground bus.
- A 6 AWG pigtail should be provided from the test stand ground lug to the test specimens.
- An 3 AWG wire should be run from the ground bus to each of the other equipment rack frames.
- A 16 AWG wire should be run from the ground bus to the ground jack on each cransducer power supply.

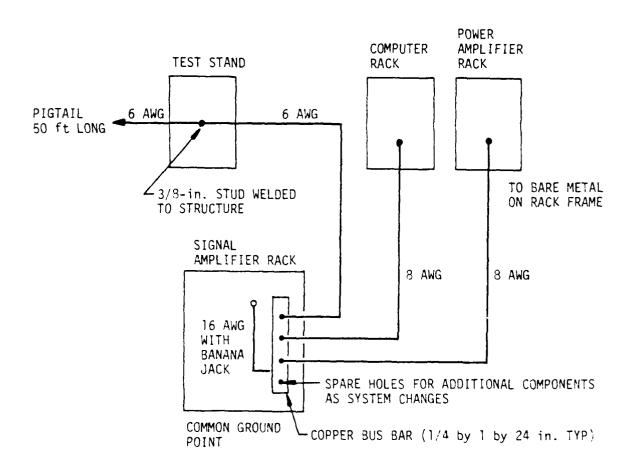


FIGURE 4-1. RECOMMENDED SIGNAL GROUND SCHEME

This grounding scheme should establish an analog ground system independent of ac third-wire grounding and substantially reduce 60-Hz noise in the system.

4.2.3 Cable Retest

At least once a year the test of Appendix A (Cable Continuity and Impedance) should be rerun to reverify the integrity of all cables, especially those on the test floor. This test can be run in approximately 8 hours and will identify any damaged cables.

Whenever an individual cable is suspect, the test can be run to the cable in a matter of minutes and the problem corrected before continuing testing.

4.2.4 Automatic System Checkout

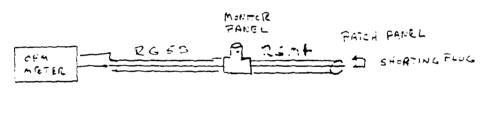
In addition to the above-mentioned recommendations, an automatic pre- and post-test checkout should be considered. The H.P. computer has the capability of acquiring and testing all transducer channels automatically. This capability can be used to run a power spectral density measurement on all transducers prior to activation of the shakers. This test can be set to flag any transducer that shows a 60-Hz frequency or other component that is above the system quiescent noise level (established after all system modifications are complete). The verification can be rerun at the completion of each test or after each shaker reconfiguration, thereby verifying that no degradation in system grounding and isolation has occurred during the test. This test should be run with the programmable filter in the bypass mode.

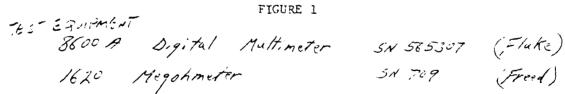
APPENDIX A. RESISTANCE TEST

RESISTANCE TEST

The purpose of this test is to verify the integrity of all wiring from the test floor to the patch panel. Using the equipment as shown in figure 1 conduct the following test and record the results in table 1.

- o Short Circuit Resistance: Connect a shorting plug to the cable at the patch panel and measure the total resistance, shield to center conductor at the floor end of the cable. For those wires stoping at the monitor panel install the shorting plug at that point.
- o Megohn Test: With all patches and shorting plugs removed, measure the open circuítry resistance of the wires with a megohmmeter.





LOOR WIRE	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGGAR TEST (V=0
	5.5	1.4K MEG
2	4,6	
3	8,7	-
4	4.6	/
5.	4,5	20K NEG
6	4,5	18% rEG
7.	4.5	
8	4.5	1.4 KMEG
9.	4, 4	/
10	4,3	
//	4.4	5K MEG
12	49	3.2 K MEG
13	4.3	/
14	4.7	50K NEG
15	4.4	1.5 K MEG
16	4,3	
17	4.8	
18	48	1/
19	4.9	/
20	4.7	13.65 MEG
21	4.4	IX rieg
22	4.9	GK MEG

TABLE 1

FLOOR WIRE	RESISTANO SHORT AT	CE WITH PATCH/PANEL	MEGGAR TEST
23	4.3	1, 3	/
24	4.3	.	/
25	4,3	*	<u></u>
26	4.3	· ,	/
27	5,0	··	1.6K MEG
28	5,2	ý .5	
_29	4,3		LOK MEG
30	9,5		/
31	4.3	9,0	/
32	4.3	9,0	1.5 K MEG
33	4.6	9,3	/
34	4.3	9.0	/
35	4.3	9.0	2K MEG
36	4.3	9,0	/
37	4.3	9.0	5K MEG
38	4,3	9,0	/
39	4.7	9,5	\ <u>\</u>
40	6.3	11.6	low resistance
41	4,8	9,6	1
42	4,4	9,1	V
43	4.8	9.5	HOK MEG
44	5.0	9.7	/

FLOOR WIRE	RESISTANC SHORT AT	E WITH PATCH/PANEL	MEGGAR TEST
45	4,4	9.1	✓
46	5,7	10,4	3K MEG
47	51	9,8	/
48	4.7	9.4	IK MEG
49	4.3	9,0	/
50	4.4	9,/	/
51	4,3	8,9	5K MEG
52	11.9	16,6	5K MEG
53	4.4	9,1	
54	4.9		/
<u>-55</u>	4.8		IK MEG
56	4.6		/
57	4.4		/
58	4.8		20K MEG
59	4.6		/
60	4.6		5K MEG
6/	5.9		\ <u>\</u>
62	4.3		13K MEG
63	4.8		/
64	4.4		/
65 66	5,4		IOK MEG
66	4.5		OK MEG GK MEG

FLOOR WIRE NO.	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGGAR TEST
67	4.6	2.8 K MEG
68	4,7	5K MEG
69	4.5	✓
70	4,5	4K MEG
7/	4.5	/
72	4,6	5K MEG
<u></u>	4.7	7K MEG
74	4.5	4K MEG
75	4.5	5K MEG
76	5,0	
77	4.5	✓
78	4,6	4K MEG
79	4.6	7K MEG
80	4.6	4K MEG
8/	4,6	/
82	5,0	✓
83	4.5	5K MEG
84	4.6	IK MEG
85	4.6	\checkmark
86	13.7	/
87	4.6	20K MEG
88	4.6	600 MEG

TABLE 1

FLOOR WIRE NO.	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGGAR TEST
89	4.6	/
90	4.6	✓
91	4,6	
92	4,6	/
93	4.5	600 MEG
94	4.6	/
95	4.5	5K MEG
96	4,5	/
97	4.8	/
98	4,6	
99	4,5	/
100	4.9	/
/01	1.2	/
102	1.2	IOK MEG
103	1.2	JOK MEG
104	1.2	
105	1.2	
106	1.2	17K MEG
157	102	/
108	1,2	IK MEG
109	1.2	3K MEG
110	1.2	

FLOOR WIRE	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGGAR TEST
	1.2	10 K MEG
	1.2	1.8K MEG
//3	1.2	/
114	1.2	4K MEG
115	1.2	<u> </u>
116	1.2	/
117	1.47	/
118	/, 2	
119	1.2	20K MEG
120	1.2	/
121	1.2	/
122	1.2	/
123	1.2	GK MEG
124	1.16	GK MEG
125	152	/
126	1. 2	✓
127	1.2	/
128	1.2	IIK MEG
129	1,2	lok MEG
	1.2	
/3/	1.2	
/32	1.2	1.3 K MEG

RESISTANCE TEST

FLOOR WIRE	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGGAR TEST
133	1,2	IOK MEG
134	1.2	20K MEG
135	1.2	2K MEG
	1.2	1.6 K MEG
137	1.2	<u> </u>
	1.28	/
	1.2	$\sqrt{}$
	1.2	GK MEG
141	1.2	1.2K MEG
142	1.2	4.5K MEG
<u>/+3</u>	1.2	
144	1.2	/
145	1.2	5K MEG
146	12	/
	1.2	2.2K MEG
148	1.2	/
149	1.2	/
150	1,2	11.6K MEG
	1.5	/
152	1.25 led or 2	
153	1.12	15K MEG
154	1.3	

FLOOR WIRE NO.	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGGAR TEST
155	1.2	7K MEG
156	1,2	20K MEG
157	1.15	5K MEG
158	1.2	/
159	. 1.2	/
160	1.2	20K MEG
161	1.24	/
162	1.15	/
163	1.24	/
164	1.13	\checkmark
165	1.16	
166	1.22	/
167	1.22	/
168	1.24	V
169	1.13	/
170	125	
171	1.22	/
172	122	
173	1.25	/
174	1.25	20K MEG
175	7.1*	
176	1.23	4K MEG

RESISTANCE TEST

FLOOR WIRE	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGGAR TEST
177	1.15	IK MEG
178	1.23	<u> </u>
	1.2	✓
180	1.2	/
181	1.23	/
182	1,23	<u> </u>
183	1.24	/
184	1.6	2.4K MEG
185	1.6	600 MEG
186	1.52	4.5K MEG
187	1.63	/
188	1.5	/
189	1.0	20K MEG
190	1.63	/
	1.6%	20K MEG
	16	
193	1.6	/
	1.63	/
195	1.6	\checkmark
196	1.62	<u> </u>

RESISTANCE TEST

FLOOR WIRE	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGGAR TEST	
		·	

APPENDIX B. INPUT PREAMPLIFIER TEST

INPUT PREAMPLIFIER TEST

The purpose of this test is to measure the gain, frequency response and distortion of the custom pre amplifiers. From the patch panel measure the performance of each amplifier channel at the following frequencies and input signal amplitudes. (Distortion at 20, 80 & 200 Hz only)

INPUT AMPLITUDE: 30 mv., 300 mv, 600 mv.

INPUT FREQUENCY (Hz)2, 10, 20, 30, 40, 80, 140, 200

HT 2 (42) Himplifiers were measured with store

THE VTVM RESPONSE POESN'T GO DOWN THAT NOW

TRSTEQUIPMENT
FUNCTION GA. From System

4000 VTVM SN 22985 (MP)

330E Distortion Praymer SN 204-08440 (MP)

Sugge with two vertical ignits

AMP CH # 1

Excita Freque	tion ncy/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN
	2	686		(10 · · · · · · · · · · · · ·	
-	2	880ms f to f		6.18 VOLTS	
1	0	320 mv	3.2 VOLTS	6.6 VOLTS	
→ 2	0	320 mv	3.2 VOLTS	6.6 VOLTS	. 34 %
3	0	320 mu	3, 2 VOLTS	6.6 VOLTS	
4	0	320 m	3. 2 voits	6.6 VOLTS	
* 8	0	320 mg	· '	6.6 VOLTS	. 3%
14	0	320 mv	3, 25 _{VOLTS}	6.6 VOLTS	
* 20	0	320 m		6.6 VOLTS	. 3%

AMP CH # 2

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
2	880 my Ptc P	3,11 VOLTS	6.18 VELTS		
10	320 pv	32 YOLTS	6. TVOLTS		
→ 20	320 mv	3.2 VOLTS	6.6 VOLTS	. 36%	
30	320mu	3,2 VOLTS	6.6 v		
40	320 60	3.2 VOLTS	6,6v		
★ 80	320 mi	3.2 YOLTS	6.6	.3%	
140	320 m	3, 2 VOLTS	6.7V		
→ 200	320 mu	3,2 VOLTS	6.65y	. 37.	

AMP CH # 3

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
2		711			
	880 mv P +0P	3.11 VOLTS	6,18 YOLTS		
10	320 mv	3,2 VOLTS	6.6 VOLTS		
* 20	320mv	3.2 VOLTS	6.6 V	. 36%	
30	320 mu	3.2 VOLTS	6.6 v		
40	320 mi	3.2 VOLTS	6.6V		
₩ 80	320 ms	3.2 VOLTS	_	.3%	
140	320 mv	3.2 VOLTS	6,6 V		
★ 200	320 mv	3,2 VOLTS	6.6v	.37.	

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
_					-
2	880m. PtcP	3.11 VOLTS	6,18 YOLTS		
10	320 mg	3.2 VOLTS	6.6 VOLTS		
→ 20	320 mV	3.2 YOLTS	6.6 v	. 36%	
30	320 mv	3,2 VOLTS	6.6v		
40	320 mi	3, 2 VOLTS	6.6v		
★ 80	320 mg	3.2 vol75	6.64	. 3%	
140	320 mv	3.2 VOLTE	G.65V		
★ 200	320 mv	3,2 VOLTS	6.65v	.3%	

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
2		21/10.70			
2	EEC my Pto P	3,11 VOLTS	6.18 VC-TS		
10	320 mv	3.2 VOLTS	6.6 VOLTS		
* 20	320 mv	3.2 YOLTS	6.6v	. 36%	
30	320 ms	3.2 VOLTS	6.6v		
40	320 mv	3,2 VOLTE	6.6v		
₹ 80	320 m	3.2 VOLTS	6.60	.37.	
140	320 mv	3.2 VOLTS	6.6 v		
→ 200	320 mv	3.2 VCLTS	6.6v	.3%	

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
2	ECCMY PAP	3.11 VOLTS	6.18 VCLTS		
10	320 mg	3.2 VOLTS	6.6 VOLTS		
* 20	320 mv	3.2 VOLTS	6.6v	. 36%	
30	320 mu	3.2 VOLTS	6.6v		
40	320 mi	3.2 VOLTS	6.6v		
★ 80	320 m	3.2 VOLTS	6.60	. 3 %	
140	320 m	3.2 VOLTS	6,6v		
★ 200	320 mv	3.2 vaits	6.61	. 3%	

AMP CH # 7

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN
2	3// mu	3,11 YOLTS	6.18 VOLTS	
10	320 mv	3.2 VOLTS	6.6 VOLTS	
≠ 20	320 mv	3.2 VOLTS	6.6v	.36%
30	320 ms	3,2 VOLTS	6.6v	
40	320 m	3.2 VOLTS	6.6v	
₩ 80	320 mi	3.2 VOLTS	Gilev	.3%
140	320 mv	3,2 va75	6,65V	
★ 200	320 mv	3,2 NELTS	6.65v	. 3%

AMP CH # Z

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
2	311 mv	3.11 VO4TS	6,18 VC175		
10	320 mv	3.2 VOLTS	6.6 VOLTS		
* 20	320 mv	3.2 VOLTS	6.6v	. 36%	
30	320 mu	3,2 VOLTS	6,6v		
40	320 mi	3.2 VOLTS	6.6v		
≠ 80	320 mu	3.2 volts	6.60	.3%	
140	320 mu	32 voits	6.6v		
× 200	320 mv	3.2 VOLTS	6.6x	. 3%	

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN
2	311 mx	3.11 VOLTS	6.18 VCLTS	
10	325 mv	3,2. VOLTS	6.6 VOLTS	
* 20	320 mu	3.2 VOLTS	6.6v	. 36%
30	320 mu	3.2 VOLTS	6.6v	
40	320 mi	3,2 VOLTS	6.6v	
★ 80	320 my	3.2 VOLTS	6.6v	. 37.
140	320 mv	3.2 VOLTS	6.6v	
* 200	320 mv	3.2 VOLTS	6.6 v	.3.5

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
2	311 _{rev}	3.11 VOLTS	6.18 VCLTS		
10	320 mg	3.15 VOLTS	6.6 VOLTS		
≠ 20	320 mv	3.2 VO_TS	6.6v	.36%	
30	320 ms	3.2 VOLTS	6.6v		
40	320 m	3,2 VCLTS	6,6v		
≠ 80	320 mv	3.2 VOLTS	G.60	.3%	
140	320 mi	3,2 yars	6.61		
× 200	320 mi	3.2 volts	6.6v	. 376	

AMP CH # //

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
2		2	(, (,) ,		
2	3/1 _{mv}	3.11 VOLT5	6.18 VOLTS		
10	320 mg	3.2 VOLTS	6,6 VOLTS		
₩ 20	320 mv	3,2 VOLTS	6.6v	. 36%	
30	320 mu	3.2 VOLTS	6.6v		
40	320 mg	3,2 VCLTS	6.60		
₩ 80	320 mu	3.2 VOLTS	6.6v	.3%	
140	320 my	3.2 VOLTS	6,6v		
⊀ 200	320 mu	3,2 vous	6.6v	. 376	

AMP CH # /2

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
2	311 mv	3.11 VOLTS	6.18 VOLTS		
10	320 mv	3.2 VOLTS	6.6 VOLTS		
→ 20	320 mv	3.2 volts	6.55 VOLTS	. 36%	
30	320 mv	3.2 vorts	6.6 v		
40	320 mu	3.2 vol-5	6.6v		
₹ 80	320 mi	3,2 YOLTS	6.6v	. 3%	
140	320 mv	3.2 VOLTS	6.60		
-x 200	320 m	3,2 VCLTS	6.6v	. 3%	

AMP CH # /3

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
•		7	() ()		
2	3/1mv	311 YOUTS	6.18 YOUTS		
10	320 mg	3.2 VOLTS	6,6 VOLTS		
* 20	320 mv	3.2 VOLTS	6.6 v	. 36%	
30	320 ms	3.2 VOLTS	6.6v		
40	320 mv	3.2 VOLTS	6.6v		
★ 80	320mu	3.2 VOLTS	6.6v	. 3%	
140	320 mv	3.2 volts	6,6V		
★ 200	320 mu	3.2 VOLTS	6.6v	. 370	

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
2	311	3.11 VOLTS	6.18 VOLTS		
10	311 mv 320 mv	3.2 VOLTS			
→ 20	320 m.v	3.2 VOLTS	6.6 v	. 367。	
30	320 mu	3.2 VOLTS	6.6v		
40	320 mu	3.2 VOLTS	G.60		
★ 80	320 mi	3.2 VOLTS	6.6v	.3%	
140	320 mu	3,2 vol75	6.6v		
→ 200	320 mu	3.2 VOLTS	6.6v	.3%	

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN
2	311mv	311 VOLTS	6.18 VOLTS	
10	320 mu	3.2 VOLTS	6,6 VOLTS	
** 20	320 mv	3.2 VOLTS	6.6 v	. 36%
30	320 mv	3.2 VOLTS	6.6v	
40	320 mv	3.2 VCLTS	6,6v	
★ 80	320 mu	3.2 VOLTS	6.60	.3%
140	320 mv	3.2 VCLTS	6.65V	
→ 200	320 mv	3.2 VOLTS	6.65v	.3%

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
2	311 mv	3.11 VOLTS	6.18 VOLTS		
10	320	3.2 VOLTS	6.6 VOLTS		
≠ 20	320 mV	3.2 VOLTS	6.6 VOLTS	. 34%	
30	320 mu	3.2 VOLTS	6.6v		
40	320 mu	3.2 VOLTS	6.60		
★ 80	320 mu	3.2 VOLTS	6,6v	.37	
140	320 mv	3,2 VOLTS	G.6v		
→ 200	320 mu	3,2 VCLTS	6.61	. 37.	
 ≠ 20 30 40 ≠ 80 140 	320 mV 320 mV 320 mU 320 mU 320 mU 320 mV	3.2 VOLTS 3.2 VOLTS 3.2 VOLTS 3.2 VOLTS 3.2 VOLTS	6.6 VOLTS 6.6 V 6.6 V 6.6 V	. 3 %	

AMP CH # 17

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
2	311 mv	3.11 VOLTS	6.18 VOLTS		
10	320 mi	3.2 VOLTS	6.6 VOLTS		
* 20	320 mv	3.2 YOLTS	6.6 VOLTS	. 34%	
30	320 mv	3.2 VOLTS	6.6v		
40	320 mu	3.2 VOLTS	6.6v		
₩ 80	320 mu	3.2 VOLTS	G.60	. 3%	
140	320 mv	3,2 volts	6.6v		
→ 200	320 mv	3,2 velts	6.6v	. 37.	

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
2	311 mv	3.11 VOLTS	6,18 YOLTS		
10	320 mu	3.2 VOLTS	6.6 VOLTS		
* 20	320 mv	3,2 VOLTS	6.6 VOLTS	. 34%	
30	320 mv	3.2 Voz-6	6.6v		
40	320 m	3. 2 verts	6.60		
≠ 80	320 mu	3.2 VOLTS	G.60	.37.	
140	320 mv	3,2 years	6.6v		
→ 200	320 my	3,2 VILTS	6.6v	. 3%	

AMP CH # 19

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN
2	3//m/	3.11 YOLTS	6.18 VOLTS	
10	320 av	3,2 VOLTS	6,6 volts	
₩ 20	320 mv	3.2 VOLTS	6.6 volts	. 34%
30	320 m	32 VOLTS	6.6v	
40	320 mu	3.2 vol+s	6.6v	
₩ 80	320 mu	3.2 VOLTS	6.6v	. 37.
140	320 mv	3.2 VOLTS	6.6v	
★ 200	320 mv	32 VOLTS	6.6v	. 3%

AMP CH #20

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
2	3/1 mv	3.11 VOLTS	6.18 VOLTS		
10	320 mu	3.2 YOLTS	6.55 VOLTS		
→ 20	3/8 mv	3.2 VOLTS	6.55 VELTS	. 34%	
30	320 mu	3,2 VOLTS	6,55v		
40	320 mu	3. 2 VOLTS	6.6v		
≠ 80	320 m	3.2 VOLTS	6.6u	. 3 %	
140	320 mV	3,2 volts	6,55v		
→ 200	320 mv	3.2 V	6,55v	. 3%	

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN
2	3/1 mv	3.11 YOLTS	6.18 VOLTS	
10	320 mv	3.2 VOLTS	6,6 VOLTS	
* 20	320 mv	3,2 VOLTS	6,55 volts	.34%
30	320 mJ	3.2 VOLTS	6.6v	
40	320 m	3.2 VOL-5	6.6v	
₹ 80	320 mJ	3,2 VOLTS	6.60	.37.
140	320 mr	32 voz-5	6.60	
→ 200	320 mu	3,2 VOLTS	6,6v	. 37.

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN
2	311 mv	3.11 VOLTS	6.18 YOLTS	
10	320 mv	3.2 VOLTS	6,6 VOLTS	
≠ 20	320 mu	3.2 VOLTS	6.6 VOLTS	. 34%
30	320 mv	3.2 VOLTS	6.6v	
40	320 mu	3.2 VOLTS	6.6v	
→ 80	320 mu	3.2 volte	6.6v	.3%
140	320 m	3,2 ve=75	6,6v	
→ 200	320 mv	3,2 VOLTS	6.64	. 3%

AMP CH # 23

Tucitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
2	311 mv	3.11 VOLTS	6.18 YOLTS		
10	320 mi	3.2 VOLTS	6.6 UOLTS		
** 20	320 mv	3.2 VOLTS	6,6 volts	. 34%	
30	320 ms	3.2 VOLTS	6.6 v		
40	320 mv	3.2 VOLTS	6.6v		
√ 80	320 mu	3.2 VOLTS	6,6v	. 3 %	
140	320 mv	3.2 VOLTS	6.60		
→ 200	320 mv	3.2 VOLTS	6.6 v	. 3%	

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
2	311 mv	3.11 VOLTS	G.18 VOLTS		
10	320 mu	3.2 VOLTS	6.6 VOLTS		
≠ 20	320 mv	3.2 VOLTS	6.6 VOLTS	. 34%	
30	320mu	3, 2 VOLTS	6,6 v		
40	320 mu	3.2 VCLTS	6.6v		
⊀ 80	320 mu	3,2 VOLTS	6.60	.370	
140	320 mv	3,2 VELTS	6.6v		
× 200	320 mv	3.2 VELTS	6.6v	. 37.	

AMP CH #<u>25</u>

Excita Freque	ation ency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
	2	311mv	3.11 VOLTS	6,18 VOLTS		
]	10	320 mx	3.2 VOLTS	6,6 VOLTS		
→ 2	20	320 mu	3.2 VOLTS	6.6 VCLTS	. 34%	
3	30	320 mv	3,2 VC, ~5	6.6 v		
4	•0	320 mu	3.2 VOLTE	{		
→ 8	30	320 mJ	3, 2 VOLTS	G.60	.375	
14	•0	320 mv	32 vol75	6.65v		
→ 20	00	320 mi	3,2 VC175	6.65v	, 37 _e	

AMP CH #26

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
2	311 mv	3.11 VOLTS	6.18 VOLTS		
10	320 my	3.2 VOLTS			
≠ 20	320 mv	3.2 VOLTS	6.6 VC= TS	. 34%	
30	320 mv	3,2 VOLTS	6.6 V		
40	320 mu	3.2 VOLTS	6.60		
₹ 80	320 mu	3,2 VOLTS	G.60	. 2 %	
140	320 mv	3,2 VELTS	6,6v		
★ 200	320 mv	3.2 VCLTS	6.6v	3%	

AMP CH # 27

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion ≠ @ 300 mv IN
2	311 my	3.11 VOLTS	6.18 VOLTS	
10	320 mv	3,2 YOLTS	6.6 VOLTS	
≠ 20	320 mu	3. 2 VOLTS	6.6 VOLTS	.34%
30	320 mv	3.2 VOLTS	6.6v	
40	320 mu	3.2 VOLTS	6.6v	
₩ 80	320 ms	3,2 VOLTS	G.60	, 3%
140	320 mg	3,2 VELTS	6,6v	
→ 200	320 mv	3, 2 velts	6,6v	. 3 %

AMP CH # 28

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN
2	311 mv	3.11 VOLTS	6.18 VOLTS	
10	320 m	3.2 VOLTS	6.6 VOLTS	
→ 20	320 mv	3.2 VOLTS	6,6 VOLTS	.36%
30	320 m	3.2 vo-T5	6.6 v	
40	325 mu	3.2 Voz.75	6.6v	
₹ 80	320 mu	3.2 volts	6.60	.3%
140	320 mg	3.2 VOLTS	6.6v	
→ 200	320 mg	3.2 VOLTS	6,650	. 3%

AMP CH #29

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
2	311 mv	3,11 VOLTS	6.18 VOLTS		
10	320 mv	3.2 VOLTS	6.6 VOLTS		
** 20	320 mv	3.2 VOLTS	i i	, 34%	
30	320 mv	3.2 VOLTS			
40	320 mv	3.2 VOLTS	6.6v		
★ 80	320 ms	3.2 VELTS	G. GU	.3%	
140	320 mg	3.2 VOLTS	6,65v	_	
→ 200	320 mi	3.2 VCLTS	6.65v	.3%	

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
2	311 mv	3.11 VOLTS	G.18 VOLTS		
10	320 mv	3.2 VOLTS	6.55 VOLTS		
₩ 20	320 m	3.2 VOLTS	6.55 VOLTS	. 34 %	
30	320 mv	3.2 VOLTS	6,55v		
40	320 mg	3.2 VOLTS	6.6v		
≠ 80	320 mv	3.2 VOLTS	6.6v	.3%	
140	320 mg	3,2 VOLTS	6.60		
* 200	320 mu	3,2 40175	6.6v	. 3%	

itation quency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion ≠ @ 300 mv IN	
2 .	311 mu	3.11 VO-TS	6.18 VOLTS		
10	320 mv	3.2 VOLTS	G. 6 VOLTS		
÷ 20	320 mV	3.2 YOLTS	6,6 VOLTS	.34 %	
30	320 mu	3.2 VOLTS	6.6 v		
40	320 m	3.2 VOLTS	6.6v		
80	320 m	3.2 VOLTS	G.6v	. 3%	
140	320 mv	3.2 VOLTS	6.6 V		
200	320 ms	3.2 yours	6.6V	. 3%	•
	2 10 20 30 40 80 140	2 311 mu 10 320 mv 10 320 mv 20 320 mv 30 320 mv 30 320 mv 30 320 mv 40 320 mv 80 320 mv 140 320 mv	Itation quency/Hz 30 mv Input % With 300mv Input % 2 3/1 mu 3.11 VO-TS 10 320 mv 3.2 VOLTS 20 320 mv 3.2 VOLTS 30 320 mv 3.2 VOLTS 40 320 mv 3.2 VOLTS 80 320 mv 3.2 VOLTS 140 320 mv 3.2 VOLTS	tation 30 mv With 300mv Input 600mv Input 2 311 mu 3.11 VO-TS 6.18 VOLTS 10 320 mv 3.2 VOLTS 6.6 VOLTS 420 320 mv 3.2 VOLTS 6.6 VOLTS 30 320 mv 3.2 VOLTS 6.6 VOLTS 40 320 mv 3.2 VOLTS 6.6 VOLTS 6.	Station 30 mv With With 600mv Input 300 mv IN

AMP CH #32

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN
2	311 mv	3.11 VOLTS	6.18 YOLTS	
10	320 mv	3.2 VOLTS	6.6 VOLTS	
* 20	320·mv	3.2 VOLTS	6,6 VOLTS	. 34 %
30	320 mv	3,2 VOLTS	6.6 v	
40	320 mu	3.2 VOLTS	6.6v	
⊭ 80	320 mv	3.2 VCLTS	6,60	. 3%
140	320 mv	3,2 VILTS	6.6v	
× 200	320 mu	3,2 veus	6.6 v	. 3%

	ation ency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
	2					
	10					
*	20					
	30		·			
	40					
*	80					
1	40					
* 2	00					

itation quency/Hz	Output with 30 mv Input %	Output With 300mv Imput	Output With 600mv Input	Distortion * @ 300 mv IN	
					
2					
10					
× 20					
30					
40					
80					-
140					
200					
	2 10 2 20 30 40 80 140	2 10 20 30 40 80 140	1 tation 30 mv With 300mv Input 2 10 2 2 30 30 40 80 140	1	10

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
2					
10					
* 2 0					
30					
40					
≠ 80					
140					
⊀ 200					

APPENDIX C. GROUNDING TEST

GROUNDING TEST

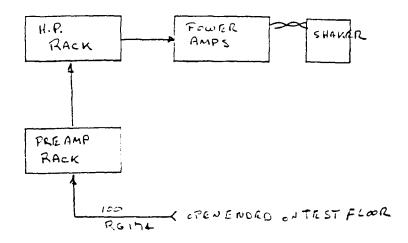
The purpose of this test is to investigate the adequacy of the system A.C. ground. Configure the system as shown in figure 2. With the H. P. system running, make the following A.C. Voltage measurements.

H.P. Rack to Preamp Rack	VOLTAGE <u>11,5 mill-vol</u> TS
H.P. Rack to Power Amp Rack	1,6 MV
H.P. Rack to Test Stand	34 mv
Preamp Rack to Power Amp Rack	4.7 mV
Preamp Rack to Test Stand	3C mV
Power Amp Rack to Test Stand	39 mv 7.7 mv D.C.

Connect a ground strap between the following points and repeat the measurements.

	VOLTAGE	
H.P. Rack to Preamp Rack	3.8 mv	22 mv P.C.
H.P. Rack to Power Amp Rack	1.2 mv	1.4 mv 0, C.
H.P. Rack to Test Stand	11 MV	10 MV D.C.
Preamp Rack to Power Amp Rack	2.9 mv	very low D.C
Preamp Rack to Test Stand	9.3 mv	NO O.C.
Power Amp Rack to Test Stand	1.1 mv	3.6 D.C.

FIGURE 2



TEST CONDITIONS

- o Sine Sweap Ø to 200 Hz
- o All Power Amps On
- o All Shakers @ ½ Power
- o All input and power supplies connected through patch panel

TESTEQUIPMENT
8600A Digital Multimeter SN 585307 (Fluke)

APPENDIX D. POWER AMPLIFIER TEST

POWER AMPLIFIER TEST

The purpose of this test is to determine the frequency response, distortion, and phase shift of the power amplifiers. Connect the equipment as shown in figure 3 and measure each amplifier performance at the following fequencies and power settings.

Input frequency 2, 10, 20, 30, 40, 80, 140, 200 output power (WATTS) 10, measure the amplifier distortion with shaker loaded to .5 and 1g. at 20, 100 and 200 Hz

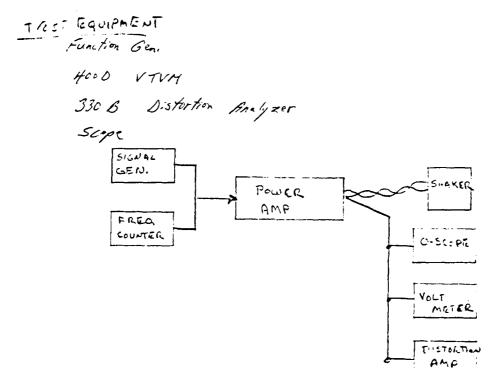


TABLE 3

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OUTPUT POWER

INPUT FREQUENCY	10 WATTS	50 WATTS	/00 WATTS
2	3.11 volts	5.65 volts	8.1 volts
10	4.6 volts	8.7 volts	11:6 volts
20	4,8 voHs	9.2 velts	12.5 volts
30	4.8 volts	9.0 volts	12.5 volts
40	4.7 volts	9.0 volts	12.5 volts
80	4.8 volts	9.2 volts	12.5 volts
140	4.8 volts	9,0 vol45	12,5 vel+s
200	4.8 volts	9.0 volts	12.5 volts

	50	100			
	DISTORT	ION @	PHASE	SHIFT @	
INPUT FREQUENCY	*	332	**	*	
20	.3 to.4%	.49.		76	
100	32%	.470		o•	
200	.370	.35%		0.	

TABLE 3

OUTPUT POWER

INPUT FREQUENCY	10 WATTS	50 WATTS	WATTS
2	2.7 volts	5.4 VOLTS	7.4 VOLTS
10	4.1 volts	8.2 VOLTS	11.0 VOLTS
20	4.4 volts	8,7 VOLTS	12.0 VOLTS
30	4.4 volts	8.7 VOLTS	12,0 VOLTS
40	4.3 volts	8.7 YOLTS	12.0 VOLTS
80	4.4 volts	8.7 YOLTS	12.0 YOLTS
140	4.4 volts	8,7 VOLTS	12.0 VCLT5
200	4.4 volts	8.7 YOLTS	12.0 VOLTS

56

DISTORTION @

100

DHACE	SHIFT	a
PHANE.	30161	10

	22010111		
INPUT FREQUENCY	-		•
20	.470	.4%	7° phase sn -
100	.3470	.35%	0"
200	.34%	.370	 0.

TABLE 3

OUTPUT POWER

INPUT FREQUENCY	10 WATTS	50 WATTS	WATTS
2	27 YOLTS	5,6 VOLTS	7.7 VOLTS
10	40 VOLTS	8.4 YOLTS	11,5 VOLTS
20	4.2 VOLTS	8.8 VOLTS	12.0 VOLTS
30	4.2 VOLTS	8.8 VOLTS	12.0 VOLTS
40	4.2 VOLTS	8.8 VOLTS	12.0 VOLTS
80	4.2 VOLTS	8,8 VOLTS	12,0 VOLTS
140	4.2 volts	8.8 VOLTS	12.0 VOLTS
200	4.2 VOLTS	8,8 VOLTS	12.2 VOLTS

INPUT	50 DISTORT	IOO @	PHASE	SHIFT @
FREQUENCY	-		35	
20	.6 to .7%	. 470		70
100	.37.	,35 %		0°
200	.3%	. 32 %	!	0°

TABLE 3

	~~
OUTPUT	POWER

INPUT FREQUENCY	10 WATTS	50	/ <i>0</i> 0
2	2.9 vo Hs	6.0 volts	7.9 volts
10	4.2 volts	8,8 volts	11.5 volts
20	4.4 volts	9.2 vo 45	12,2 volts
30	4,4 volts	9.2 volts	12.0 volts
40	4,4 volts	9,2 volts	12,0 volts
80	4.4 xolts	9.2 volts	120 volts
140	4,4 velts	9,2 volts	12.2 volts
200	4.4 yoits	9,2 volts	12.2 volts

50

100

DISTORTION @

PHASE SHIFT @

INPUT FREQUENCY			
20	4%	.570	7°
100	4%	.670	0
200	.370	.4670	0°

APPENDIX E. FREQUENCY SYNTHESIZER CALIBRATION RECORD

PERFORMANCE TEST CARD

Test Performed By H.J. Frey Hewlett-Packard Model 3320A/B Frequency Synthesizer Serial No. 1532 BO 1586 Frequency Accuracy Vernier Out 1,000,000 .999990 MHz 1 MHz 1.000010 MHz 12.219992 12.22 MHz 12.219878 MHz 12.220122 MHz 1.10 MHz 1.099989 MHz 1.100011 MHz 00.01 MHz عبر 999900 و9 عبر 100.00100 يعر Vernier In 15.095 00.0150 MHz 14.000 kHz 16,000 kHz 12.9999 MHz 12.9989 MHz 13.0009 MHz 1000 kHz Range 0000 100 kHz Range 100 10 kHz Range 1000 Hz Range 300 **Harmonic Distortion** Not Not 10 kHz Checked 129.9 kHz > - 60 dB > - 50 dB > - 50 dB 150 kHz > - 40 dB 1299 kHz > - 40 dB 4 MHz 7 MHz > - 40 dB 12,99 MHz > - 40 dB **Spurious** > - 60 dB or - 110 dBm Signal to Phase Noise > - 40 dB Not charted 3320A Amplitude Accuracy 50 Ohm load 0.9 V rms 1.1 V rms Open circuit 1.8 V rms 2.2 V rms 3320B Amplitude Accuracy 5.01 50 Ohm loed 4.975 V rms 5.025 V rms 10.04 Open circuit 9.95 V rms 10.05 V rms Frequency Response 3320A - 0.8 cm + 1 cm +0.1 3320B, 0.01 Hz-10 Hz -0.2 cm + 0.2 cm 6970 to 7034 3320B, 10 Hz-13 MHz 6930 µV dc 7070 µV dc Adjusted Errors: Adjusted Errors: (Para. 5-22(e)): C in the formula A = B + C - D 1299 kHz | 1 kHz | .1 kHz 12.99 kHz 12.99 MHz .01 MHz 129.9 kHz

				IBRATII		CORD				/ 3
INSTRUMENT		ĺOV			NA ENGI	NEEDING	DATE		PAGE	<u> </u>
Frequency.	Synthesizer		<u> </u>	5AF			10211	4-	12-79	,
MANUFACTURER N.	í. p	MC	ODEL	3320	OB		SERIAL	NUMBER 1531	R 1015	-86
TECHNICIAN		DA	TE OF LAST	CALIBRATIO	DN		NEXT !	DUE DATE	10000	
AMBIENT TEMPERATU	IRE	ни	MIDITY	Neu			PROCEI	DURE		
	7005			480				Hamis	atures	
ADJUSTMENT REQUIRE	ED REMARKS				f	OUIRED - RE	EMARKS	18 6		
☐ YES ☑ NO		·			□ YES			(NE 105	1	
				DA	ATA					
NOMINAL READING OF ITEM BEING CALIBRATED	INITIAL READING OF CALIBRATING EQUIPMENT		AIC ERROR B FROM A	OF ITEM	ACCURACY M BEING ATED %	ACCEPT/ ERRO		GREAT	AIC ERROR ER THAN BLE ERROR	FINAL READING AFTER REPAIR OR ADJUSTMENT
A	В	•	D	1	£	F		462	NO H	1
1 Hz	1000018 usa		1						1	
2 Hz	499996 MSC	1	1							
5Hz	200000 4500		Insti	Luneal	1 nce	& Man	enfact	Lores	Soecs	
10 Hz	100000 MSR			X the		aling ex			1	
20 Hz	5000/ USE				ريدر ا	orton -	Courie	2,5		
30 Hz	33333MSPC		5	ana/-	40.04	ase No	bise	عروام	chache	
40 Hz	25000 MSec		7	Tue x		f of				
50 Hz	2000/USEC		1	Quipm			1		1	
60Hz	16666 MSE		7		**************************************					
80 Hz	12500 usec				*****			1		
100 Hz	10000 USE									
120 Hz	8333 MSR			1				1		
140 Hz	7/42 MSec									
200 Hz	5000 USA		1					i		
	1			<u> </u>						
	1									
	1		†	 				1		
		<u> </u>	1	EQUIPME	NT USE	0				
DESCRIP	PTION, CALIBRATION DA	TE AND AC	SENCY		<u> </u>	DESCRIP	TION CAL	LIBRATION	DATE AND A	AGENCY
5245L 0	ounter			504-	03969		6-2	,- <i>>9</i> _		73E
545B Sco					0777		6-7-			78E
	9 - 14				2439		9-20			78E
88588 019	Yothmeter				195		9-6-7			Flote
93/8 RH	S DIFF Vette	neter		13	91		-3.7			Fluke
110498 THE	ermal Carro				00238		-3/-7			NP
355D VHF	Attenuator				0/743		-8-7			78E
	s Valtareter				29/9/05		1-12-7			TBE
FORM 7035, REV.										
I Cer	rtify that this Calibra	ation is T	raceable to	and Com	patible wit	th National	Bureau r	of Standa	rds Measur	ement.
			,		i ; \mathcal{L}	bel	10	Aff_	-	ļ
		_			<u> </u>	tus.	211	4		'

Supervisor Calibration Laboratory

Attenuator Accuracy, 33208 (Para. 5-24(d)): D in the formula A = B + C - D

+ 15.00 dBm	0.998 V dc	<u>. 999</u>	1.002 V dc
+ 5.00 dBm	0.996 V dc	1.000	1.004 V dc
- 5.00 dBm	0.994 V dc		1.006 V dc
- 15.00 dBm	0.992 V dc	. 998	1.008 V dc
- 25,00 dBm	0.990 V dc	1998	1.010 V dc
- 35.00 dBm	ob V 889.0	<u>-997</u>	1.012 V dc
- 45,00 dBm	0.986 V dc	<u>•998</u>	1.014 V dc
- 55.00 dBm	0.984 V dc		1.016 V dc
- 65.00 d8m	0.982 V dc		1.018 V dc

Attenuator Frequency Response, 3320B Record Readings (Para. 5-26(d)): B in the formula A = B + C - D

	Record Readings	(Step d):					
	12.99 MHz	.01 MH2	1299 kHz	1 kHz	129.9 kHz	12.99 kHz	1299 Hz
+ 15		1488	-299	.999	- 599	Licec	1999
+ 5		1.001	1001	1.001	1.001	1.001	1.001
٠ 5		1.001	1000	1.000	1.000	1.000	1,000
- 15		1.001	1.001	1.001	1.001	1.001	1.001
- 25		1.000	1,000	1.001	1.000	1.000	1.000
- 35		1,000	1.000	1,000	1.000	1.000	1.000
- 45		1.000	1.000	1.001	1.000	1.000	1.001
· 5 5							
- 65				ļ			

Calculated Error (Para, 5-26(h)): A in the formula A = B + C - D

				•				•
_	12.99 MHz	.01 MHz	1299 kHz	1 kHz	129.9 kHz	12.99 kHz	12.99 Hz	Tolerance
+ 15		0	186	14	-114	8€	14	± 5 mV
+ 5								± 5 mV
- 5						l ——		± 12 mV
- 15								± 12 mV
- 25								± 23 mV
- 35								± 23 mV
- 45								± 23 mV
- 55								± 45 mV
- 65		· !						± 45 mV

DATE FILMED